Test Org.*	Device	Function	Technology	Mfr.	Effective SEU LET* Threshold	Device Xsection (cm^2)	Bits Tested	Bit Xsection (cm^2)	Test Date	LUth	LU Xsection (cm^2)	Fac.	Remarks 15-Sep-99
		ADC (14-bit)											
	Note: Entries in **RED** indicate data added since the 1997 Compendium.												
JPL	AD7872TQ	Serial Output	BiCMOS	ADI	~1.4	1.0E-03			Sep-92	>104			Slight differences in all "1s" and "0s".
JPL	**AD9240**	**10 MSPS Binary parallel output**	**CMOS**	**ADI**						**25**	**6.0E-04**	**TAM**	**Miyahira, preliminary JPL internal report.**
JPL	**AD9243**	**3 MSPS Binary parallel output**	**CMOS**	**ADI**						**25**	**6.0E-04**	**TAM**	**Miyahira, preliminary JPL internal report.**
JPL	**ADS-946-2**	**parallel output**	**CMOS**	**DAT**						**7.7**	**4.0E-06**	**TAM**	**Miyahira, preliminary JPL internal report.**
JPL	LTC1419		CMOS (epi?)	LTN	16	3.0E-05			Mar-97	>74		BNL	X-section @ LET = 40. Used 1 KHz sine wave input. Separate JPL report 6/97.
Legend													
	Manufacturers: ADI - Analog Devices, Inc; DAT - Datel; LTN - Linear Technology												
	Test Organizations			**Radiation Test Facilities**									
	JPL - Jet Propulsion Laboratory, Pasadena, CA			BNL - Tandem Van de Graaff, Brookhaven National Laboratories, Long Island, NY									
				TAM - Texas A&M University Cyclotron Institute, College Station, TX									